

# **Depleted** monolithic active pixel sensor (DMAPS) – R&D towards high-radiation and high-rate environment

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## **CMOS pixels (in commercial processes) for HEP**



#### First MAPS-based vertex detector



#### MIMOSA28 (ULTIMATE) for STAR Design led by IPHC Strasbourg Twin-well 0.35 μm CMOS Rolling shutter => ~200 μs int. time ~ 0.16 m<sup>2</sup> => 356 M pixels



ALPIDE for ALICE Design led by CERN Quadruple-well 0.18 μm CMOS Sparse r.o. matrix => 10 μs int. time ~ 10 m<sup>2</sup> => 12 G pixels





Still many to come Mu3e, CBM-MVD, sPHENIX, ... Future e<sup>+</sup>-e<sup>-</sup> colliders ? HL-LHC (p-p) ?

#### 2011 2016 Beyond 2018

- R&D motivated by the need of highly granular sensors with very low material budget
  - Especially attractive and already successful for heavy-ion experiments
  - Proposed also for future e<sup>+</sup>-e<sup>-</sup> collider experiments
- Progressively evolve towards higher radiation tolerance and faster readout
  - Exploit advances in commercial CMOS technologies + dedicated designs => HL-LHC (p-p) ?

## **Depleted MAPS for ATLAS @ HL-LHC**



 Strong R&D momentum in the ATLAS community to achieve radiation hard MAPS through depletion towards ATLAS @ HL-LHC



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## **Depleted MAPS for ATLAS @ HL-LHC**



- DMAPS has already been considered for the outermost pixel layer of ATLAS ITk
  - low cost and easy module assembly
  - require significantly enhanced rad. tolerance & speed w.r.t. the well established MAPS

|                                 | STAR     | ALICE-LHC            | ILC              | ATLAS-HL-LHC     |                    |
|---------------------------------|----------|----------------------|------------------|------------------|--------------------|
|                                 |          |                      |                  | Outer            | Inner              |
| Fluence [n <sub>eq</sub> /cm²]  | 1012     | $1.7 \times 10^{13}$ | 10 <sup>12</sup> | 10 <sup>15</sup> | 2x10 <sup>16</sup> |
| TID [Mrad]                      | 0.2      | < 3                  | 0.4              | 80               | > 1000             |
| Required timing                 | ~ 200 µs | 20 µs                | O(1 μs)          | 25 ns            | 25 ns              |
| Hit Rate [kHz/mm <sup>2</sup> ] | 4        | 10                   | 250              | 1000             | 10 000             |

Non-ionizing radiation (displacement damage)
 => fast collection by drift

depletion

- Time resolution
  - => fast collection by drift
  - => fast analog FE for small time walk
  - => time stamping

- High hit rate
  - => short pulse duration (< 1 μs)
  - => high readout bandwidth
  - => massive on-chip mem.
    - (long trig. Latency > 10  $\mu$ s)

- 1. HV add-ons to apply > 50 V bias I. Peric, DOI: 10.1016/j.nima.2007.07.115
- 2. **HR substrate** wafers (or epi)  $d \sim \sqrt{\rho \cdot V}$ 
  - 100 Ω·cm kΩ·cm
  - convergence of N<sub>eff</sub> after high fluence (> 10<sup>15</sup> n<sub>eq</sub>)
    acceptor removal + deep acceptor introduction

#### 3. Multiple nested wells

- high voltage shielding
- full CMOS in pixel

#### 4. Backside processing

- thin sensor (100 200  $\mu$ m) with backside bias
- Design mostly implemented in "medium" feature size processes 130 nm -350nm
  => AMS 350 nm, AMS/TSI 180nm, LFoundry 150 nm, GlobalFoundry 130 nm, ESPROS 150 nm, TowerJazz 180 nm, IBM T3 130 nm, STM 180 nm, ON Semi 180 nm, SOI XFAB 180 nm





## Sensor design approaches



- Electronics inside charge coll. well
- Large charge collection electrode
  => resemble standard n-in-p sensor
  => no/little low field region
  => on average short(er) drift path
- Full CMOS with iso. between nw/dnw
- Large sensor capacitance (pw & dnw !)
  => noise & speed (power) penalty
  - => dedicated design to mitigate x-talk



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- Electronics outside charge coll. well
- Very small sensor capacitance (~ 5 fF)
  => lower power budget for analog FE
- Full CMOS with deep pwell
- Less prone to cross talk
- On average **long(er)** travelling path and potentially low field region
  - => process modification for rad. hardness

## **Process modification – TowerJazz 180 nm CMOS**





#### Standard process

- High res. P-type epi. (> 1 kΩ·cm)
  => typ. thickness 25 μm
- Quadruple-well
  => deep pwell shields nwell => full CMOS
- Reverse bias typ. -6 V
  - => enhanced, but not yet full depletion



#### Modified process

- Additional planar low dose N implant
  => improve depletion under deep pwell
  => fully depleted sensing volume possible
- Maintain small capacitance feature
- No significant circuit/layout changes

W. Snoeys et al. DOI: 10.1016/j.nima.2017.07.046

## **Sensor irradiation performance**

- UNIVERSITÄT BONN
- Good radiation hardness of large electrode sensor proven in various prototypes



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## **Sensor irradiation performance**

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- TowerJazz small electrode design in modified process showed promising results
  - > 97% efficiency after  $10^{15} n_{eq}/cm^2$  at low threshold (< 100 e<sup>-</sup>) for 30 µm square pixel



### **Demonstrator chips with large scale matrix**



#### LFoundry 150 nm CMOS



Large electrode Pixel size 50  $\mu$ m  $\times$  250  $\mu$ m Pixel matrix 129  $\times$  36 Thinned down to 100  $\mu$ m T. Wang, et al.,

DOI: 10.1088/1748-0221/12/01/C01039 P. Rymaszewski et al., DOI: http://doi.org/10.22323/1.313.0045 T. Hirono, et al., DOI: 10.1109/NSSMIC.2016.8069902 K. Moustakas et al., DOI: doi.org/10.1016/j.nima.2018.09.100

#### AMS 180 nm CMOS



**Large** electrode 10/80/200/1k  $\Omega$ ·cm sub. Pixel size 40µm × 130µm Pixel matrix 400 × 25 Thinned down to ~ 60 µm

I. Perić, et al., DOI: 10.1016/j.nima.2018.06.060 M. Kiehn, et al., DOI: 10.1016/j.nima.2018.07.061

#### TowerJazz 180 nm CMOS



Small electrode - MALTA:  $36.4\mu m \times 36.4\mu m$   $512 \times 512$  pixels - TJ-Monopix:  $36\mu m \times 40\mu m$   $224 \times 448$  pixels Standard/modified process Thinned down to 100  $\mu m$ T. Wang, et al., DOI: 10.1088/1748-0221/13/03/C03039 I. Berdalovic, et. al, DOI: 10.1088/1748-0221/13/01/C01023

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• The two sensor design approaches lead to different analog FE choices



#### **Charge Sensitive Amplifier**

- Used for large electrode sensor
- Gain (ideally) independent of  $C_D$ => G ~ 1/C<sub>f</sub> (Typ. C<sub>f</sub> ~ fF)
- $\tau_{CSA} \propto \frac{C_D}{g_m \cdot C_f}$ ,  $ENC_{thermal} \propto \frac{KT}{g_m} \frac{C_D^2}{\tau}$ => need larger  $g_m$  (power) for large  $C_D$ => typ. power 5 – 20  $\mu$ A
- In-pixel threshold trimming



• The two sensor design approaches lead to different analog FE choices



D. Kim et al., 10.1088/1748-0221/11/02/C02042

#### **ALPIDE like amplifier**

- Voltage amplifier

> Profit from small sensor capacitance> large voltage excursion @ input node

- Very compact design
  - => amplification + shaping in one stage
  - => simple inverter as discriminator
  - => no threshold trimming in ALPIDE
- Optimized power for required timing
  => ~ 500 nA for 25 ns peaking time

## **Readout architecture – DMAPS**

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#### DMAPS with synchronous matrix => time stamping in matrix





- Well established scheme in ATLAS FE-I3 like
  sufficient rate capability for ITk outer pixel layers
- Time reference distributed in the matrix
  => need small skew across the long column (~ 2cm for ITk)
- ToA & ToT recorded in pixel
- Hits read out following the token passing scheme on shared column bus
- In-pixel memories and digital r.o. logic
  - => digital cross talk, pixel size, C<sub>D</sub> (for large electrode design)



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#### <u>DMAPS with asynchronous</u> matrix => time stamping at periphery

=> Hits transferred to periphery immediately => call for massive parallelism



Shared bus by pixel groups





#### DMAPS with asynchronous matrix



- Analog only pixel (CSA + discri.)
  => good for cross talk to sensor, pixel size, capacitance
- All digital processing at periphery
- Complex column line routing
  - => 400 lines in two metal layers for ATLASPix
- Position dependent hit transfer latency
  - => need compensation/correction
- Larger periphery area









Monopix

MALTA

#### DMAPS with asynchronous matrix



- High speed bus by transferring short pulses (~ 1ns)
  => pulse generated by the pixel logic in case of hit
  => reference pulse + parallel pulses indicating hit pixel address
- Special routing and buffering to balance load on the column bus to ensure the multi-bit data arrive simultaneously at periphery
- Max. pulse propagation delay along ~ 2 cm column ~ 7.5 ns
- Fast data synchronization (~ GHz) needed at periphery
  => not in the current MALTA, implemented recently in a test chip
- Careful study needed on data collision caused by simultaneous hits on pixel groups of the same color





# Test results



### **Results – LF-Monopix**



- High BV ~ -280 V => large depletion + high field
- High and uniform efficiency even after irradiation
  - Achieved @ very low noise occupancy < 10<sup>-7</sup>/25ns/pixel
- Promising timing, and can be improved by
  - Optimization of analog FE biasing
  - Enhanced charge collection in thinned sensor through HV backbias





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## **Results – ATLASPix Simple**



- High efficiency after 10<sup>15</sup>n<sub>eq</sub>/cm<sup>2</sup> (neutron)
- Improved timing expected by correcting time walk based on ToT



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#### **Results – MALTA & TJ-Monopix**



• Low corner efficiency, especially after irradiation







MALTA, after irradiation

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## Fixes to improve efficiency after irradiation





**Reminder**: simulation of worst case for particle impinging at pixel corner

- Simulation shows significantly improved charge collection time and less charge loss after irradiation with both proposed fixes
- New design with both fixes submitted in August 2018
- T. Kugathasan, et al., VERTEX 2018

p<sup>-</sup> epitaxial layer

p<sup>+</sup> substrate

NMOS

pwell

pwell

#### Summary

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- Rapid progress on R&D of DMAPS for high radiation & high rate environment
  - Aiming at the outermost pixel layer of ATLAS ITk @ HL-LHC => low cost, easy assembly
  - Large demonstrator chips exist in several technologies
- Two sensor concepts pursued by the ATLAS ITk community
  - Large electrode designs are intrinsically radiation hard
    - High efficiency after  $1 \times 10^{15} n_{eq}/cm^2$
    - Promising timing, but not yet fully in time efficient (25 ns)
  - Small electrode design offers low power and smaller pixels
    - Low efficiency @ pixel corner after irradiation for the current iteration
    - Fixes implemented recently in MPW
- Still many work towards a ATLAS ready chip
  - Faster timing for in-time efficiency > 95% after irradiation
  - Chip integration and verification
  - System level aspects: serial powering, data link, sensor bias, ...
  - The future is not only exciting, but also challenging...



# Thank you!



# Back up

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• Deep sub-micro meter CMOS technology also offer good TID tolerance

TID

Combined with radiation hard by design for sensitive blocks



No significant performance loss after 50 Mrad

#### Edge TcT





A. Affolder, et al., DOI: 10.1088/1748-0221/11/04/P04007

## **Design challenges for LF-Monopix**





- Large detector capacitance  $C_d = C_{sub} + C_n + C_{pw}$ 
  - C<sub>pw</sub> tends to be **dominant** => depends on electronics area & DNW/PW junction width
  - Timing  $\tau_{CSA} \propto \frac{1}{g_m} \frac{\mathbf{C}_d}{C_f}$ - Noise  $ENC_{thermal}^2 \propto \frac{4}{3} \frac{kT}{g_m} \frac{\mathbf{C}_d^2}{\tau}$ More *power* needed to compensate =>  $\mathbf{g}_m \propto |_d$
  - Cross talk => C<sub>pw</sub> directly couples the substrate noise into the sensor
    - The minimum operation threshold may be affected

## **Readout architecture – hybrid example**

- For high hit rate capability, one would generally need
  - □ Small pixel
  - □ High logic (memory) density



I. Perić, et al., DOI: 10.1016/j.nima.2006.05.032

- □ Fast shaping
- High data transmission bandwidth
- The so-called "column drain" readout
- Hit info. recorded in pixel
  - => time of arrival (ToA), time over threshold (ToT)
  - Hit data transferred over the column bus to EoC
    - buffers following the token-passing scheme
    - => double column organization
    - => synchronous readout @ 20 MHz
- Hits stay at periphery until trigger latency
  => read out if triggered, discard if not
- Main bottleneck is column bus congestion





#### M.Garcia-Sciveres, et al., DOI: 10.1016/j.nima.2010.04.101

#### **RD53A** (65 nm, 50 x 50µm<sup>2</sup>)

**PixelRegionLogic** 



- Local hit storage within the matrix => use memory efficiently by grouping pixels into regions and exploiting the cluster feature of hits
- Hits stay in matrix until trigger latency => local trigger management
- Only transfer triggered hits to the periphery
  => relaxed column bus bandwidth requirement
- Higher logic density & smaller pixel achieved by exploiting deeper sub-micro tech. nodes

Note1: complex in-pixel logic is hard for DMAPS Note2: logic density of hybrid always > monolithic

## **Chip design strategy – LF/TJ-Monopix**





- The goal is to demonstrate a large pixel array with column drain r.o.
  - 1 2 cm<sup>2</sup> chip size
- For design simplicity, not all the peripheries expected for the final chip are included
  - Off-chip r.o. controller by FPGA
  - No trigger memory on chip
    - => All hits r.o. sequentially via a serial link
  - No high speed (Gbps) link, serial powering, etc.





50

- Optimized for < 25 ns time walk</li>
- Static current ~ 20 μA/pixel
- Full-custom dig. Circuit ٠
  - Minimized area => reduce  $C_d$
  - Special low noise design, e.g. current steering circuit

Front-end

**R/O logic** 











- We can move the in-pixel r.o. logic to the periphery
  - Discriminator output r.o. by source follower
  - Less area needed for in-pixel electronic => less  $C_d$
  - Almost no in-pixel digital transient

=> less noise/cross talk

- Almost no signal distributed in the column
- One-to-one connection from pixel to R/O logic => Complex routing

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#### **Matrix overview**





CMOS review t.wang@physik.uni-bonn.de







- Pixel size  $36 \times 40 \,\mu\text{m}^2$  => smaller than large fill factor design
- Small sensor footprint:  $2 \mu m$  diameter diode +  $3 \mu m$  spacing
- Separate digital & analog region
- Full-custom digital design
  - Minimize area



• Pixel array 224 imes 448, composed of equally divided 4 sub arrays



### Laboratory results – LF-Monopix



I. Caicedo, Bonn

- Breakdown @ -280 V => up to  $\sim$  300  $\mu$ m depletion
- ToT calibrated with sources: <sup>241</sup>Am, terbium
- Gain 10 -12 μV/e<sup>-</sup>
- Typical ENC ~ 200 e<sup>-</sup>
- Tunable threshold down to 1400 e<sup>-</sup>
  - dispersion ~ 100e<sup>-</sup>

#### **ToT vs. Injection**







15

10

5

20

X [Pixels]

30

25

0

0.003

0.000

#### **MALTA & TJ-Monopix – FE performance**





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- Lower efficiency for region with full deep P well
- Min. operational threshold increased after irradiation
  - ~ 350 e<sup>-</sup> before irrad. & ~ 550 e<sup>-</sup> after irrad.

#### **Improvement after back-side processing**







- It is assumed that in the final prototype
  - 2 double columns per r.o. unit => 512  $\times$  4 pixels
  - 20 MHz column bandwidth: 50 ns (2 BC) per hit readout
    - => a simple math: max. allowed hit rate = 1/column bandwidth = 0.5 hit/r.o.unit/BC
- Inefficiency caused by trig. memory pileup not included here => pure matrix performance
- Data loss increases steeply beyond 600 MHz/cm<sup>2</sup> => ~ 0.44 hits/r.o.unit/BC

